PROCEEDINGS OF SPIE

Advanced Optics for Imaging Applications: UV through LWIR IV

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Editors

14–15 April 2019
Baltimore, Maryland, United States

Sponsored and Published by
SPIE

Volume 10998

Proceedings of SPIE 0277-786X, V. 10998

Advanced Optics for Imaging Applications: UV through LWIR IV, edited by Jay N. Vizgaitis
Peter L. Marasco, Jasbinder S. Sanghera, Proc. of SPIE Vol. 10998, 1099801

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Author(s), "Title of Paper," in *Advanced Optics for Imaging Applications: UV through LWIR IV*, edited by Jay N. Vizgaitis, Peter L. Marasco, Jasbinder S. Sanghera, Proceedings of SPIE Vol. 10998 (SPIE, Bellingham, WA, 2019) Seven-digit Article CID Number.

ISSN: 0277-786X
ISSN: 1996-756X (electronic)

ISBN: 9781510626614
ISBN: 9781510626621 (electronic)

Published by
SPIE
P.O. Box 10, Bellingham, Washington 98227-0010 USA
Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445
SPIE.org

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